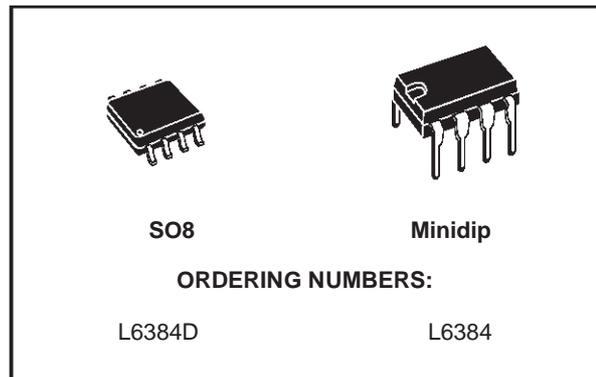


HIGH-VOLTAGE HALF BRIDGE DRIVER

- HIGH VOLTAGE RAIL UP TO 600 V
- dV/dt IMMUNITY +/- 50 V/nsec IN FULL TEMPERATURE RANGE
- DRIVER CURRENT CAPABILITY:
400 mA SOURCE,
650 mA SINK
- SWITCHING TIMES 50/30 nsec RISE/FALL WITH 1nF LOAD
- CMOS/TTL SCHMITT TRIGGER INPUTS WITH HYSTERESIS AND PULL DOWN
- SHUT DOWN INPUT
- DEAD TIME SETTING
- UNDER VOLTAGE LOCK OUT
- INTEGRATED BOOTSTRAP DIODE
- CLAMPING ON V_{CC}
- SO8/MINIDIP PACKAGES

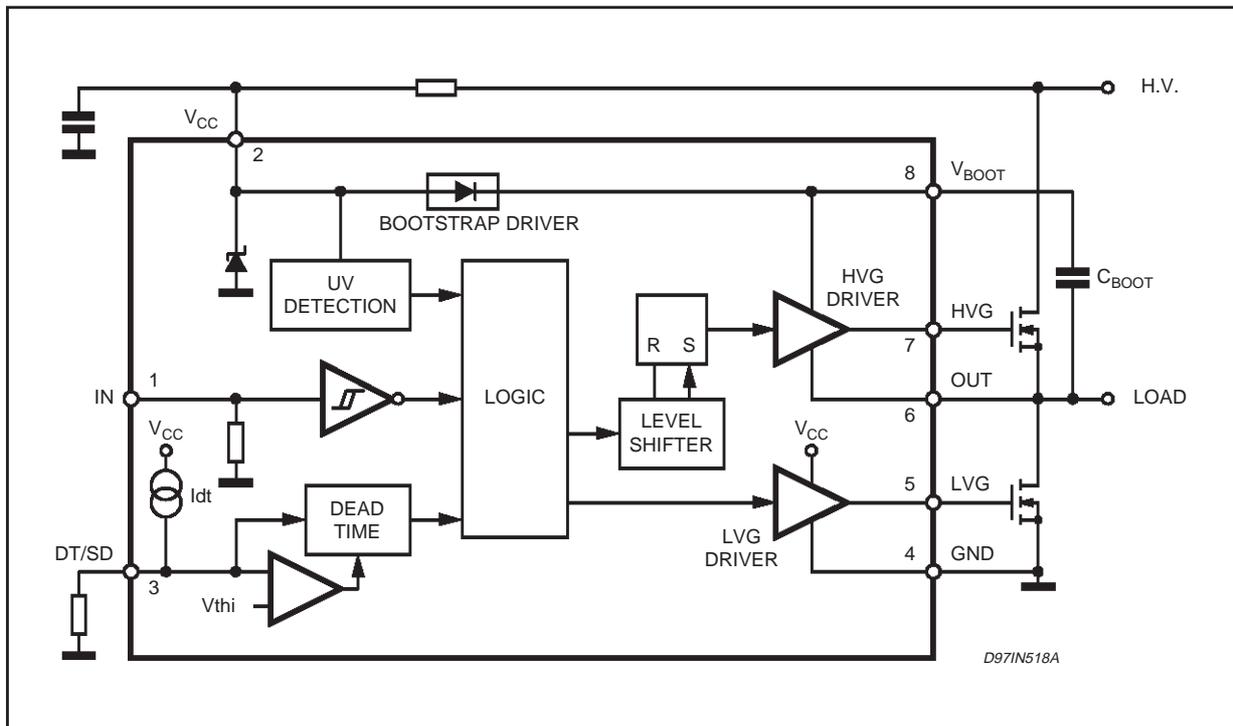


an Half - Bridge Driver structure that enables to drive N Channel Power MOS or IGBT. The Upper (Floating) Section is enabled to work with voltage Rail up to 600V. The Logic Inputs are CMOS/TTL compatible for ease of interfacing with controlling devices. Matched delays between Lower and Upper Section simplify high frequency operation. Dead time setting can be readily accomplished by means of an external resistor.

DESCRIPTION

The L6384 is an high-voltage device, manufactured with the BCD"OFF-LINE" technology. It has

BLOCK DIAGRAM

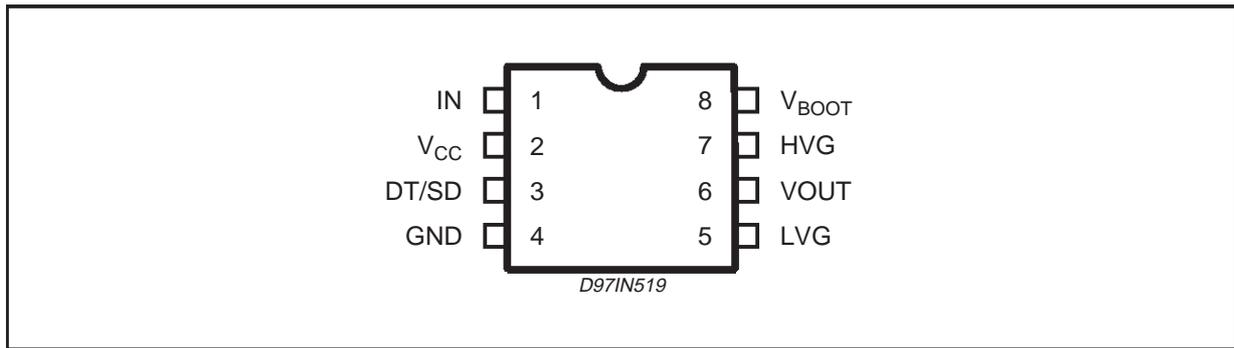


ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
Vout	Output Voltage	-3 to Vboot -18	V
Vcc	Supply Voltage (*)	- 0.3 to 14.6	V
Is	Supply Current (*)	25	mA
Vboot	Floating Supply Voltage	-1 to 618	V
Vhvg	Upper Gate Output Voltage	-1 to Vboot	V
Vlvg	Lower Gate Output Voltage	-0.3 to Vcc +0.3	V
Vi	Logic Input Voltage	-0.3 to Vcc +0.3	V
Vsd	Shut Down/Dead Time Voltage	-0.3 to Vcc +0.3	V
dVout/dt	Allowed Output Slew Rate	50	V/ns
Ptot	Total Power Dissipation (Tj = 85 °C)	750	mW
Tj	Junction Temperature	150	°C
Ts	Storage Temperature	-50 to 150	°C

(*) The device has an internal Clamping Zener between GND and the Vcc pin, It must not be supplied by a Low Impedance Voltage Source.
Note: ESD immunity for pins 6, 7 and 8 is guaranteed up to 900 V (Human Body Model)

PIN CONNECTION



THERMAL DATA

Symbol	Parameter	SO8	Minidip	Unit
R _{th j-amb}	Thermal Resistance Junction to Ambient	150	100	°C/W

PIN DESCRIPTION

N.	Name	Type	Function
1	IN	I	Logic Input, in phase with HVG driver.
2	Vcc	I	Low Voltage Power Supply
3	DT/SD (*)	I	Dead Time/Shut Down Setting
4	GND		Ground
5	LVG (*)	O	Low Side Driver Output
6	Vout	O	Upper Driver Floating Reference
7	HVG (*)	O	High Side Driver Output
8	Vboot		Bootstrap Supply Voltage

(*) The circuit guarantees 0.3V maximum on the pin (@ Isink = 10mA), with VCC >3V. This allows to omit the "bleeder" resistor connected between the gate and the source of the external MOSFET normally used to hold the pin low; the gate driver assures low impedance also in SD condition.

RECOMMENDED OPERATING CONDITIONS

Symbol	Pin	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Vout	6	Output Voltage		Note1		580	V
Vboot - Vout	8	Floating Supply Voltage		Note1		17	V
fsw		Switching Frequency	HVG,LVG load CL = 1nF			400	kHz
Vcc	2	Supply Voltage				Vclamp	V
Tj		Junction Temperature		-45		125	°C

Note 1: If the condition Vboot - Vout < 18V is guaranteed, Vout can range from -3 to 580V.

ELECTRICAL CHARACTERISTICS
AC Operation (Vcc = 14.4V; Tj = 25°C)

Symbol	Pin	Parameter	Test Condition	Min.	Typ.	Max.	Unit
ton	1 vs 5,7	High/Low Side Driver Turn-On Propagation Delay	Vout = 0V Rdt = 47kΩ		200 +dt	250	ns
tonsd	3 vs 5,7	Shut Down Input Propagation Delay			200	250	ns
toff	1 vs 5,7	High/Low Side Driver Turn-Off Propagation Delay			200	250	ns
tr	7,5	Rise Time	CL = 1000pF		50		ns
tf	7,5	Fall Time	CL = 1000pF		30		ns

DC Operation (Vcc = 14.4V; Tj = 25°C)

Symbol	Pin	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Supply Voltage Section							
Vclamp	2	Supply Voltage Clamping	Is = 5mA	14.6	15.6	16.6	V
Vccth1		Vcc UV Turn On Threshold		11.5	12	12.5	V
Vccth2		Vcc UV Turn Off Threshold		9.5	10	10.5	V
Vcchys		Vcc UV Hysteresis			2		V
Iqccu		Undervoltage Quiescent Supply Current	Vcc ≤ 11V		150		μA
Iqcc		Quiescent Current	Vin = 0		380	500	μA
Bootstrapped supply Voltage Section							
Vboot	8	Bootstrap Supply Voltage				17	V
IQBS		Quiescent Current	Vout = Vboot; IN = HIGH			200	μA
ILK		High Voltage Leakage Current	VHVG = Vout = Vboot = 600V			10	μA
Rdson		Bootstrap Driver on Resistance (*)	Vcc ≥ 12.5V; IN = LOW		125		Ω
High/Low Side Driver							
Iso	5,7	Source Short Circuit Current	VIN = Vih (tp < 10μs)	300	400		mA
Isi		Sink Short Circuit Current	VIN = Vil (tp < 10μs)	500	650		mA
Logic Inputs							
Vil	2,3	Low Level Logic Threshold Voltage				1.5	V
Vih		High Level Logic Threshold Voltage		3.6			V
Iih		High Level Logic Input Current	VIN = 15V		50	70	μA
Iil		Low Level Logic Input Current	VIN = 0V			1	μA
Iref	3	Dead Time Setting Current			28		μA

DC Operation (continued)

Symbol	Pin	Parameter	Test Condition	Min.	Typ.	Max.	Unit
dt	3 vs 5,7	Dead Time Setting Range (**)	Rdt = 47k	0.4	0.5	3.1	μs
			Rdt = 146		1.5		μs
			Rdt = 270k		2.7		μs
Vdt	3	Shutdown Threshold			0.5		V

(*) R_{DS(on)} is tested in the following way: $R_{DS(on)} = \frac{(V_{CC} - V_{CBOOT1}) - (V_{CC} - V_{CBOOT2})}{I_1(V_{CC}, V_{CBOOT1}) - I_2(V_{CC}, V_{CBOOT2})}$

where I₁ is pin 8 current when V_{CBOOT} = V_{CBOOT1}, I₂ when V_{CBOOT} = V_{CBOOT2}

(**) Pin 3 is a high impedance pin. Therefore dt can be set also forcing a certain voltage V₃ on this pin. The dead time is the same obtained with a Rdt if it is: Rdt · I_{ref} = V₃.

Figure1. Input/Output Timing Diagram

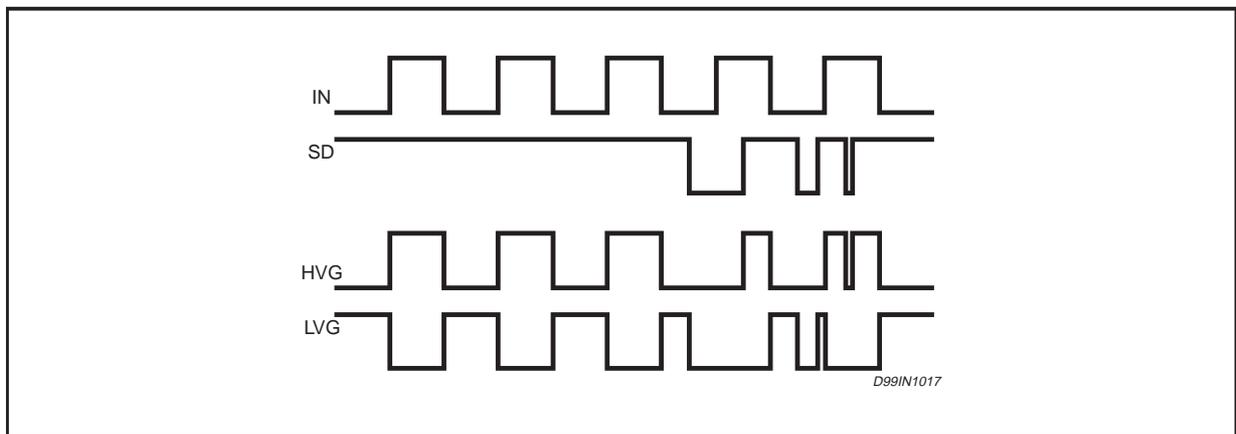


Figure 2. Typical Rise and Fall Times vs. Load Capacitance

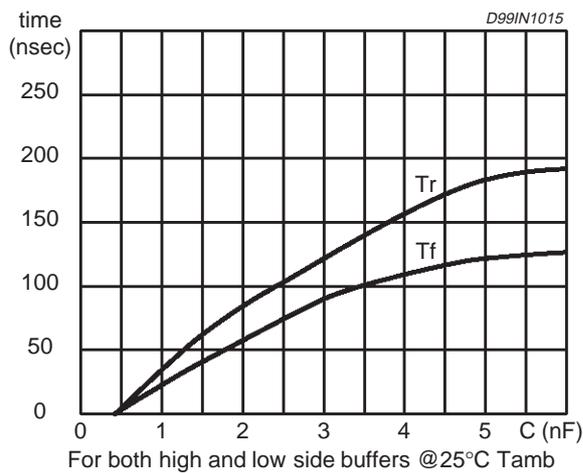
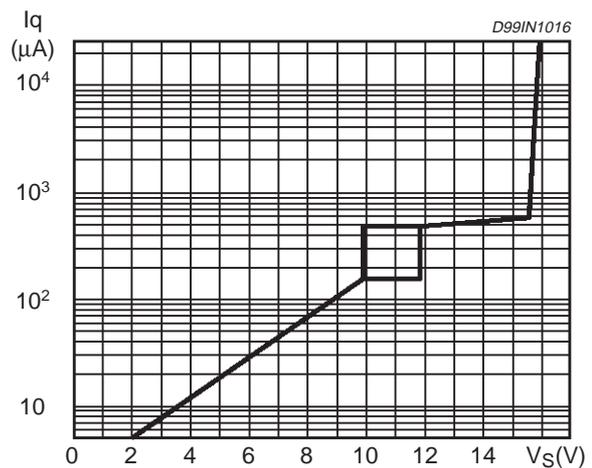


Figure 3. Quiescent Current vs. Supply Voltage



BOOTSTRAP DRIVER

A bootstrap circuitry is needed to supply the high voltage section. This function is normally accomplished by a high voltage fast recovery diode (fig. 4a). In the L6384 a patented integrated structure replaces the external diode. It is realized by a high voltage DMOS, driven synchronously with the low side driver (LVG), with in series a diode, as shown in fig. 4b

An internal charge pump (fig. 4b) provides the DMOS driving voltage.

The diode connected in series to the DMOS has been added to avoid undesirable turn on of it.

CBOOT selection and charging:

To choose the proper CBOOT value the external MOS can be seen as an equivalent capacitor. This capacitor CEXT is related to the MOS total gate charge :

$$C_{EXT} = \frac{Q_{gate}}{V_{gate}}$$

The ratio between the capacitors CEXT and CBOOT is proportional to the cyclical voltage loss .

It has to be:

$$C_{BOOT} \gg C_{EXT}$$

e.g.: if Qgate is 30nC and Vgate is 10V, CEXT is 3nF. With CBOOT = 100nF the drop would be 300mV.

If HVG has to be supplied for a long time, the CBOOT selection has to take into account also the leakage losses.

e.g.: HVG steady state consumption is lower than 200µA, so if HVG TON is 5ms, CBOOT has to

supply 1µC to CEXT. This charge on a 1µF capacitor means a voltage drop of 1V.

The internal bootstrap driver gives great advantages: the external fast recovery diode can be avoided (it usually has great leakage current). This structure can work only if VOUT is close to GND (or lower) and in the meanwhile the LVG is on. The charging time (Tcharge) of the CBOOT is the time in which both conditions are fulfilled and it has to be long enough to charge the capacitor.

The bootstrap driver introduces a voltage drop due to the DMOS RDS(on) (typical value: 125 Ohm). At low frequency this drop can be neglected. Anyway increasing the frequency it must be taken in to account.

The following equation is useful to compute the drop on the bootstrap DMOS:

$$V_{drop} = I_{charge} R_{dson} \rightarrow V_{drop} = \frac{Q_{gate}}{T_{charge}} R_{dson}$$

where Qgate is the gate charge of the external power MOS, Rds(on) is the on resistance of the bootstrap DMOS, and Tcharge is the charging time of the bootstrap capacitor.

For example: using a power MOS with a total gate charge of 30nC the drop on the bootstrap DMOS is about 1V, if the Tcharge is 5µs. In fact:

$$V_{drop} = \frac{30nC}{5\mu s} \cdot 125\Omega \sim 0.8V$$

Vdrop has to be taken into account when the voltage drop on CBOOT is calculated: if this drop is too high, or the circuit topology doesn't allow a sufficient charging time, an external diode can be used.

Figure 4. Bootstrap Driver

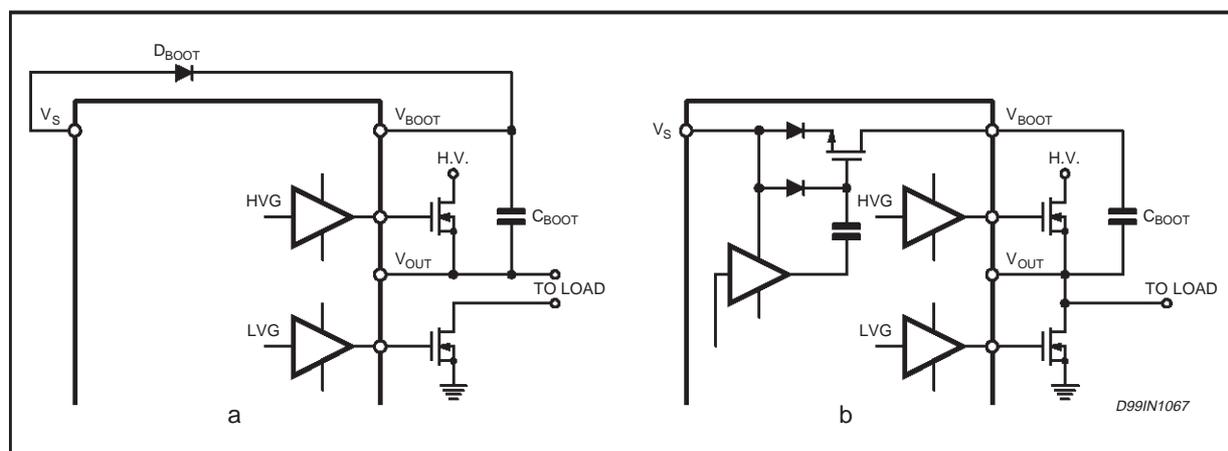


Figure 5. Dead Time vs. Resistance.

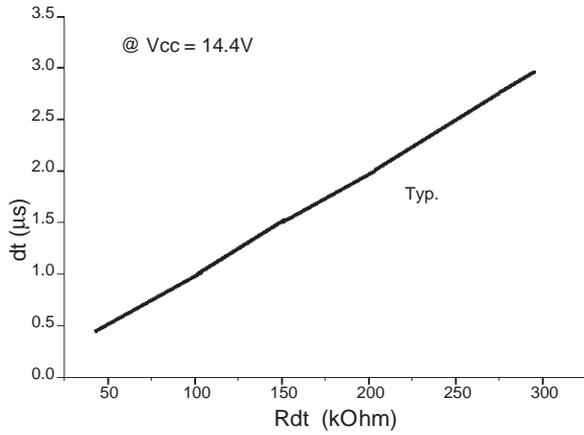


Figure 8. Shutdown Threshold vs. Temperature

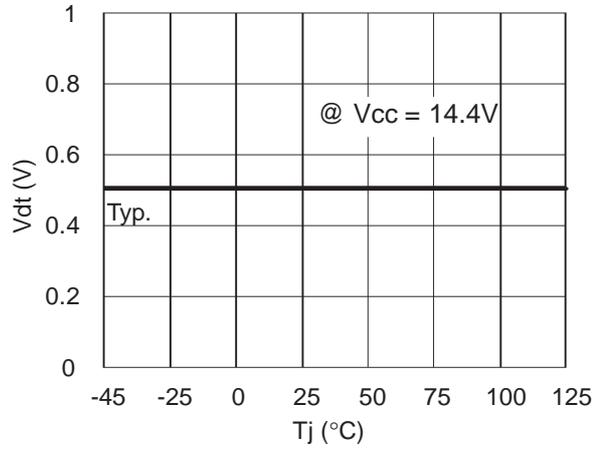


Figure 6. Dead Time vs. Temperature.

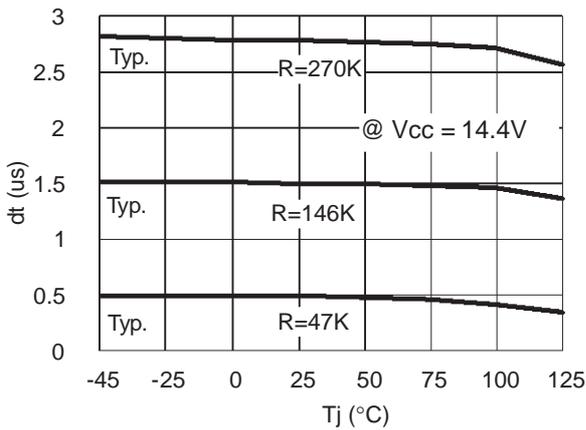


Figure 9. Vcc UV Turn On vs. Temperature

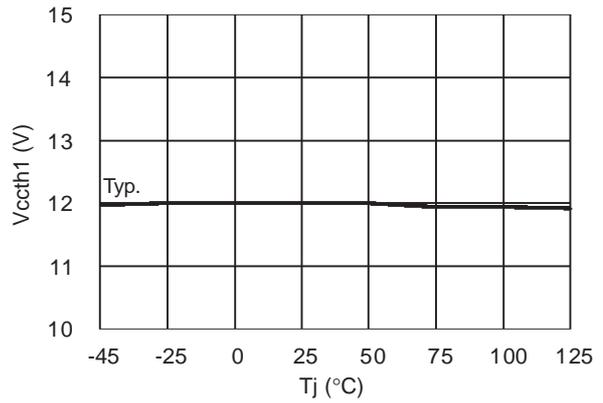


Figure 7. Driver Propagation Delay vs. Temperature.

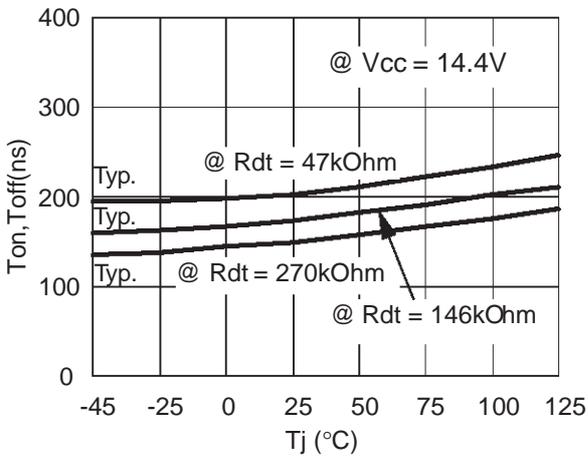


Figure 10. Vcc UV Turn Off vs. Temperature

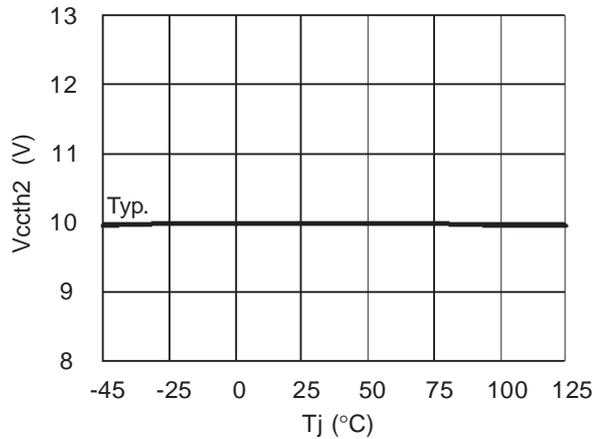


Figure 11. Output Source Current vs. Temperature.

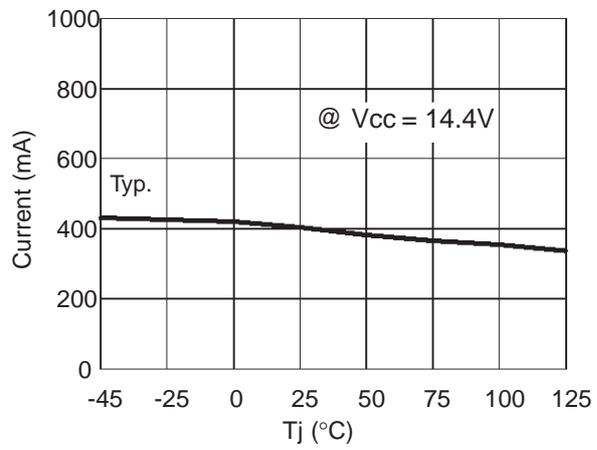
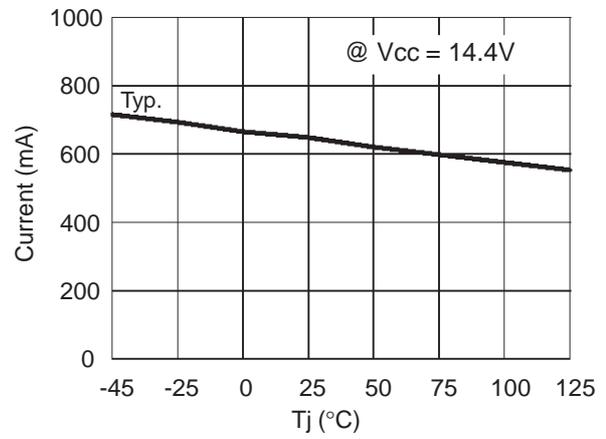
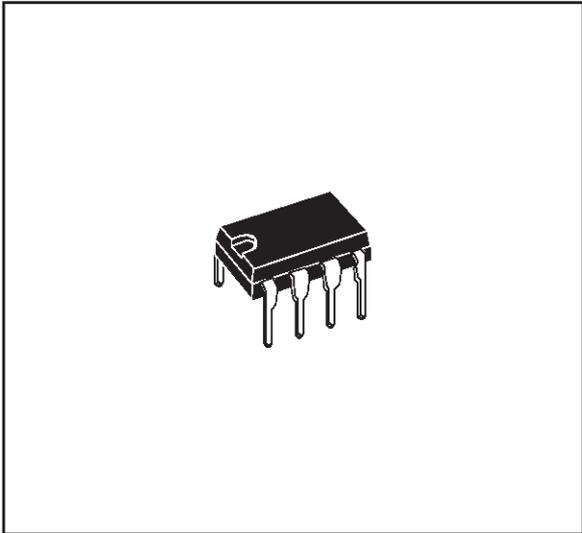


Figure 12. Output Sink Current vs. Temperature

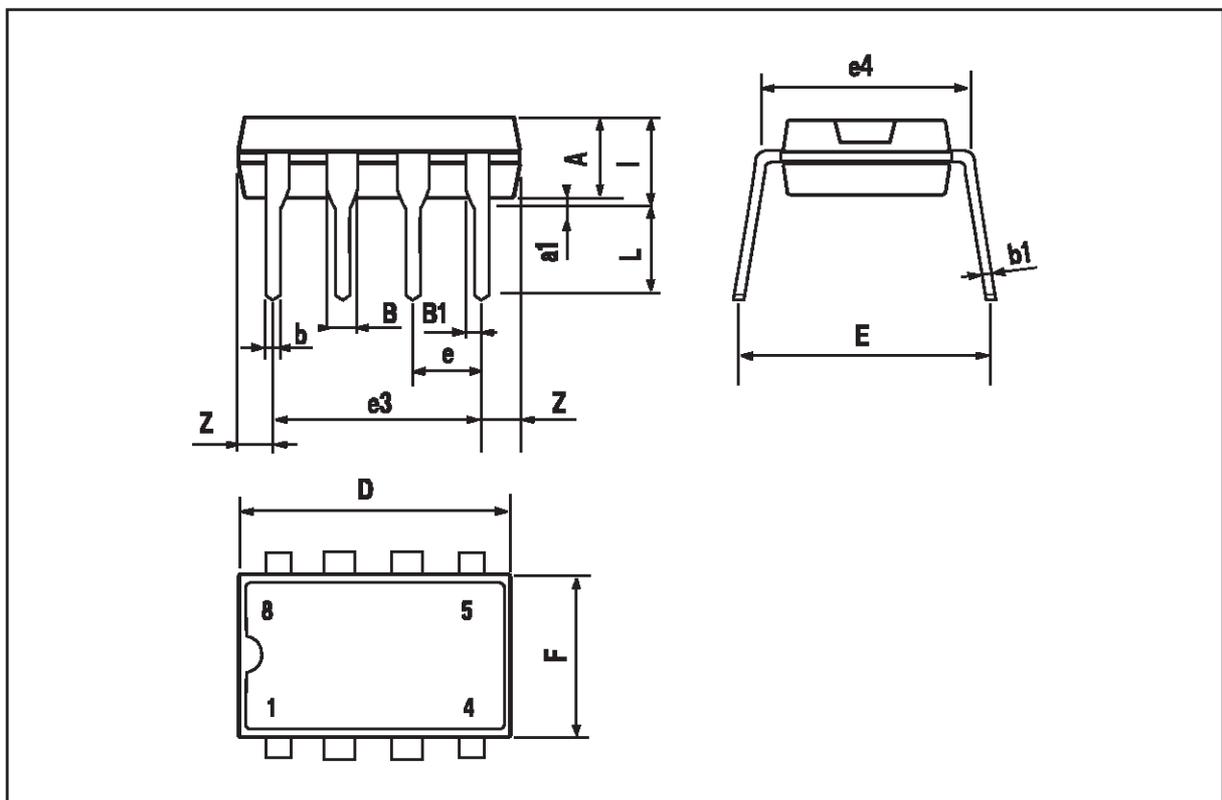


DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A		3.32			0.131	
a1	0.51			0.020		
B	1.15		1.65	0.045		0.065
b	0.356		0.55	0.014		0.022
b1	0.204		0.304	0.008		0.012
D			10.92			0.430
E	7.95		9.75	0.313		0.384
e		2.54			0.100	
e3		7.62			0.300	
e4		7.62			0.300	
F			6.6			0.260
I			5.08			0.200
L	3.18		3.81	0.125		0.150
Z			1.52			0.060

OUTLINE AND MECHANICAL DATA

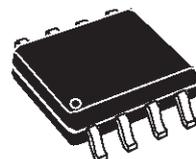


Minidip



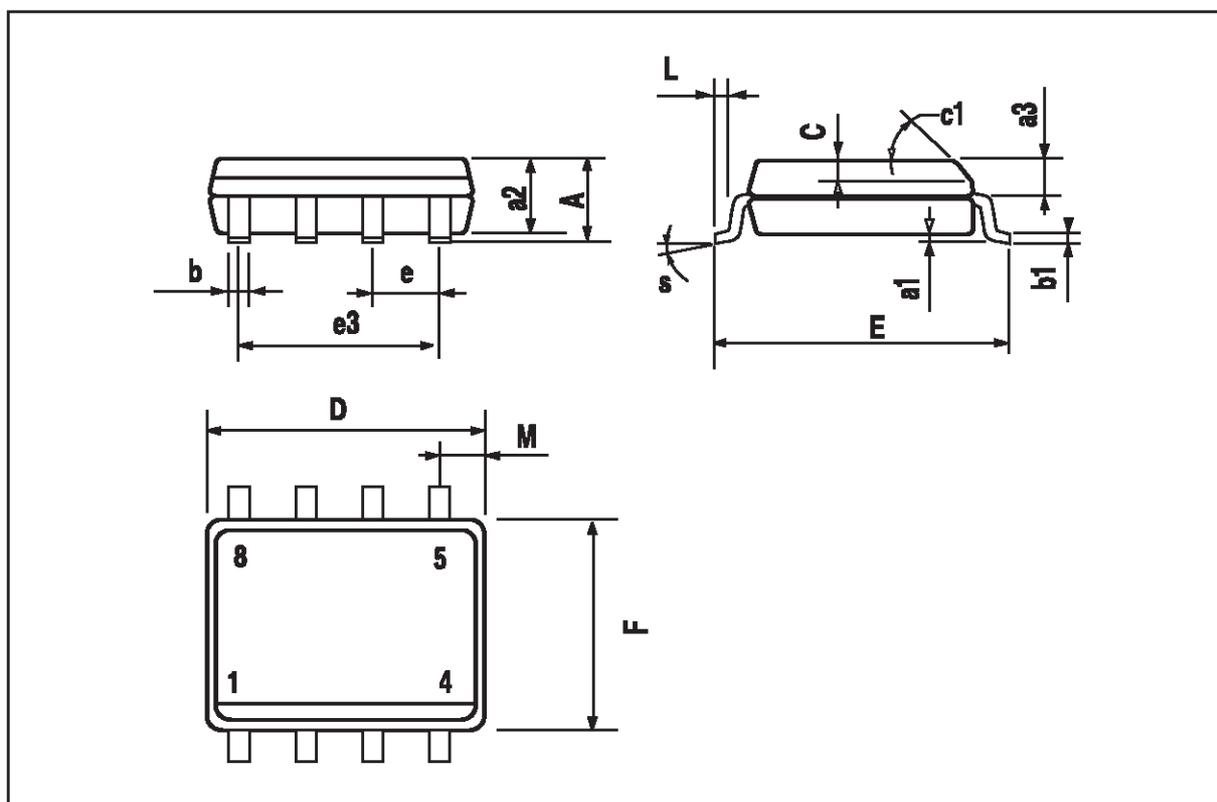
DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.069
a1	0.1		0.25	0.004		0.010
a2			1.65			0.065
a3	0.65		0.85	0.026		0.033
b	0.35		0.48	0.014		0.019
b1	0.19		0.25	0.007		0.010
C	0.25		0.5	0.010		0.020
c1	45° (typ.)					
D (1)	4.8		5.0	0.189		0.197
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		3.81			0.150	
F (1)	3.8		4.0	0.15		0.157
L	0.4		1.27	0.016		0.050
M			0.6			0.024
S	8° (max.)					

OUTLINE AND MECHANICAL DATA



SO8

(1) D and F do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.15mm (.006inch).



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